

<b>FORM PTO-1449</b> US DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty. Docket No. <b>85377LMB</b> Customer No. 01333	Serial No. <b>10/789,971</b>
If AFTER the later date of the first Office Action or 3 months from filing, use only with Rule 97(E) Certificate or Fee		
Applicant: <b>Peter T. Aylward, et al</b>		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		Filing Date <b>2-27-04</b>
		Group <b>1752</b>

**U.S. PATENT DOCUMENTS**

Examiner Initial*	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
✓	3,299,192	01-17-1967	John H. Lux			
✓	3,864,444	02-04-1975	Johnson			
✓	4,098,941	07-04-1978	Johnson			
✓	4,456,571	06-26-1984	Johnson			
✓	4,832,775	05-23-1989	Park et al.			
✓	5,084,334	01-28-1992	Hamano et al.			
✓	5,277,852	01-11-1994	Spydevold			
✓	5,667,740	07-16-1997	Spydevold			
✓	5,674,442	10-07-1997	Morita			
✓	5,851,651	12-22-1998	Chao			
✓	5,866,282	02-02-1999	Bourdelaïs et al.			
✓	6,077,065	06-20-2000	Sumiyoshi et al.			
✓	6,447,976 B1	09-10-2002	Dontula et al.			
✓	6,514,659 B1	02-04-2003	Dontula et al.			
✓	6,514,660 B1	02-04-2003	Majumdar et al.			
✓	6,537,656 B1	03-25-2003	Dontual et al.			
✓	6,566,033 B1	05-20-2003	Majumdar et al.			
✓	2003/0031747 A1	02-13-2003	Becker			
✓	2003/0031748 A1	02-13-2003	Becker			
✓	2003/0036479 A1	02-20-2003	Majumdar et al.			
✓	2003/0073577 A1	04-17-2003	Majumdar et al.			
✓	2003/0118750 A1	06-26-2003	Bourdelaïs et al.			
✓	2003/0118807 A1	06-26-2003	Laney et al.			
✓	2003/0123150 A1	07-03-2003	Brickey et al.			
✓	2003/0128313 A1	07-10-2003	Kaminsky et al.			
✓	2003/0152760 A1	08-14-2003	Lai et al.			
✓	2003/0219610 A1	11-27-2003	Aylward et al.			
✓	2003/0219663 A1	11-27-2003	Sunderrajan et al.			
✓	2003/0232188 A1	12-18-2003	Savage et al.			

**FOREIGN PATENT DOCUMENTS**

Examiner Initial*	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
✓	1 285 741 A1	02-26-2003	EP				X
✓	0 838 321 B1	12-10-2003	EP				X
✓	2839905 B2	12-24-1998	JP			X	
✓	3308733 B2	07/29/2002	JP			X	
✓	99/12722	03-18-1999	WO				X

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
1	EP01890228.8 application, filed 7/2/2001, now publication EP1285741A1
2	Japanese Abstract JP04-327937
3	Japanese Abstract JP08-132415
4	Japanese Abstract JP09-106038
5	Japanese Abstract JP09-127648
6	Japanese Abstract JP10-249915
7	Japanese Abstract JP11-023814
8	To RC or Not to RC, Crawford, Gray and Parsons, Journal of Photographic Engineering, pages 110-117 (1979)
9	Co-pending USSN _____, Aylward et al., <i>Surface Roughness Frequency To Control Pits On Foam Core Imaging Supports</i> , (D-84886)

EXAMINER <i>R I Schiller</i>	DATE CONSIDERED <i>4-6-05</i>
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>	